



Via Santa Maria Maddalena 12, 38100 Trento, Italy
tel. +39-0461-260 552 - fax + 39-0461-260 617
e-mail: info@neuricam.com; <http://www.neuricam.com>

VISTA 320 x 256 Digital Camera

PRELIMINARY DATA SHEET

Rel. 09/99

KEY FEATURES

- Full-frame CMOS active-pixel grey level image sensor with digital interface. It allows a complete digital camera to be assembled with only a few passive external components and does not require a frame grabber
- High dynamic range logarithmic response to light
- Non integrating continuous current reading pixels
- 320 x 256 -pixel resolution, 8- μ m pitch square pixels, array size 2.560 x 2.048 mm², true random read operation
- Integrated video amplifier and analog-to-digital converter with 10-bit resolution
- Sensitivity adjustment circuit for operation under different illumination conditions
- Typical sensitivity: 2 lux with f=1.2
- Acquisition rate of 2 M pixels/s, corresponding to frame rates of up to 50 frames/s
- Implemented in CMOS technology for integration of functions which require several additional chips if conventional CCDs are employed
- Single 3.3-V operating voltage
- Low operating current: 50 mA typical
- Evaluation board of single-chip camera including interface to a personal computer and software drivers available.

APPLICATIONS

- Embedded cameras
- Industrial inspection and control
- Robotics
- 3D laser object reconstruction
- Automotive

GENERAL DESCRIPTION

VISTA is a monolithic full-frame active-pixel grey level image sensor with on-chip analog-to-digital converter and microprocessor interface. It uses conventional CMOS technology and integrates video amplifier, analog-to-digital converter and a bus interface. It permits the assembly of a compact and low-cost single-chip digital camera with the addition of only a few passive components. It can be connected directly to a microcomputer or a microcontroller and is easily adapted to user requirements. The digital camera VISTA can operate at a frame rate of up to 50 frame/s with a resolution of 10 bits.

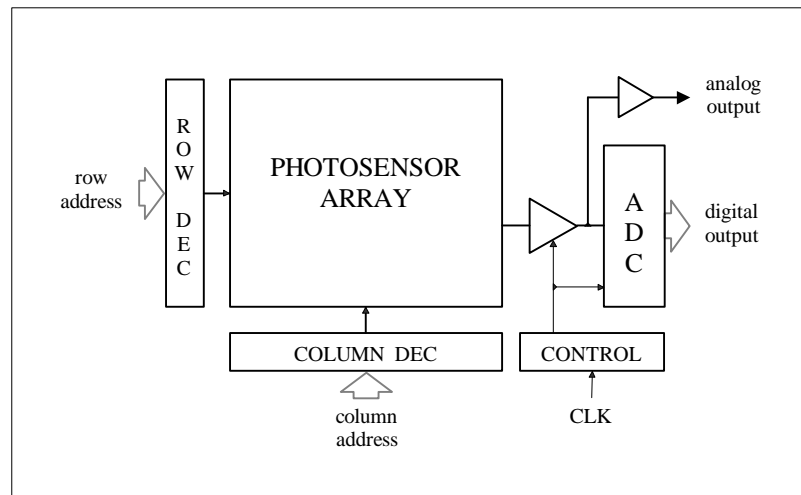


Fig. 1 Simplified camera block diagram.

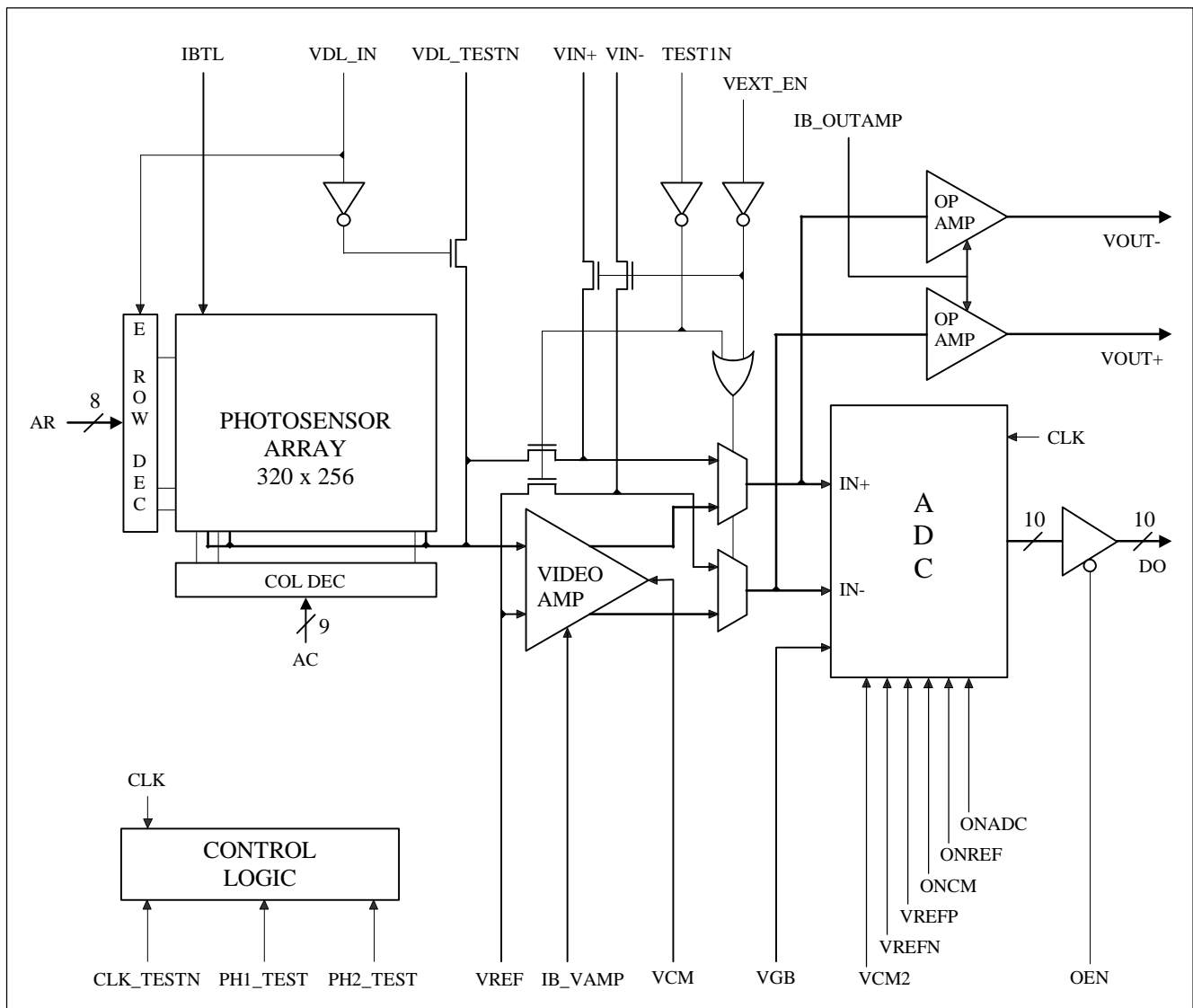
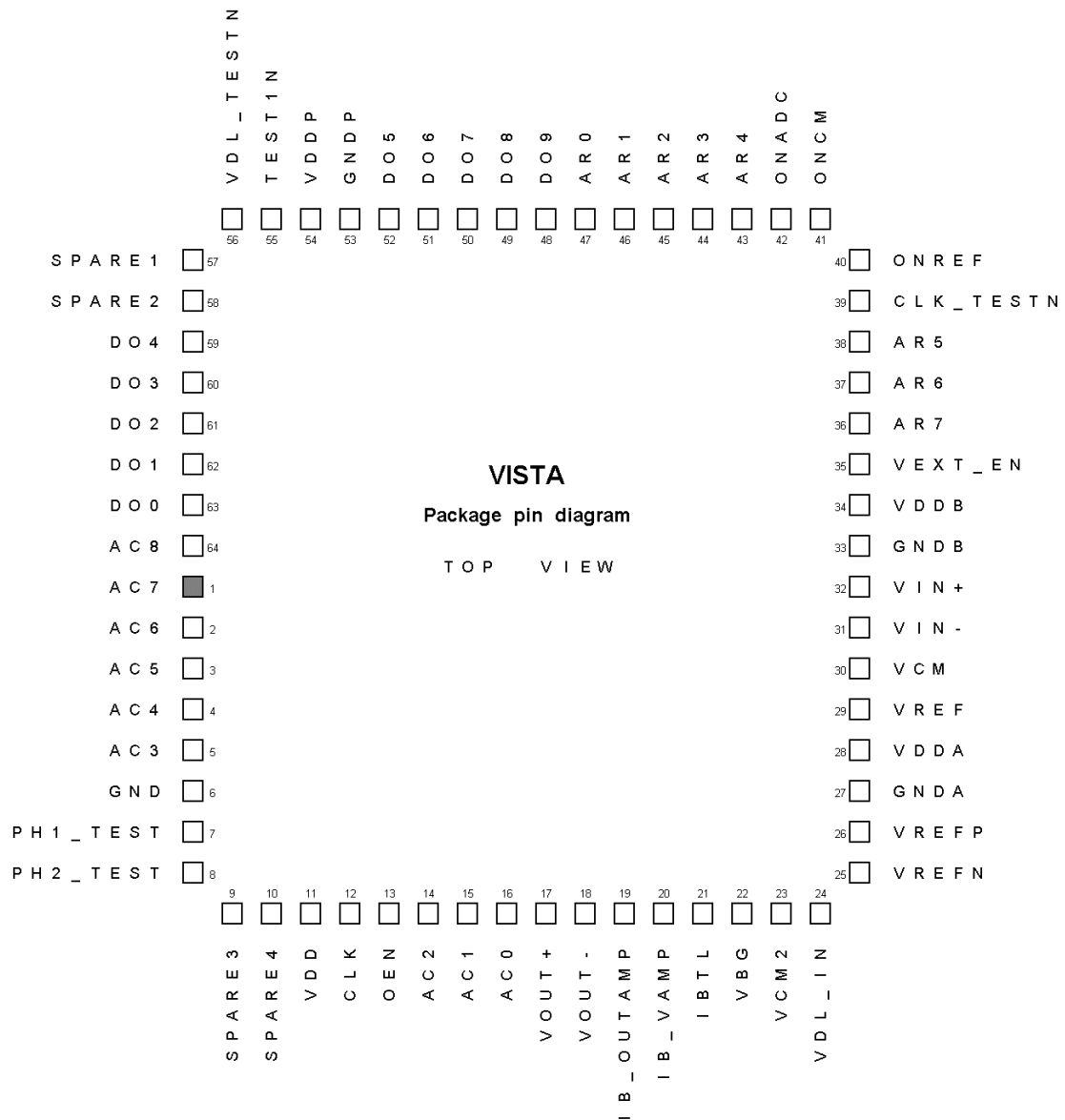


Fig. 2 Detailed camera block diagram.

PIN CONFIGURATION – 64 PIN LCC package with glass window



PIN DESCRIPTION

| PIN NAME | TYPE | DESCRIPTION |
|----------------|------|--|
| DIGITAL | | |
| CLK | DI | Clock - 20 MHz nominal - 50% duty cycle |
| AR[7:0] | DI | Row address bus. AR7 is the MSB |
| AC[8:0] | DI | Column address bus. AC8 is the MSB. Allowed range 0-319d |
| DO[9:0] | DO | Digital video data output. DO9 is the MSB. Bus can be trista-ted |
| OEN | DI | Output enable for DO output bus. Active low |
| VEXT_EN | DI | Enable VIN+, VIN- inputs. Active low |
| ANALOG | | |
| IBTL | AI | Bitline bias current |
| IB_VAMP | AI | Video amplifier bias current |
| IB_OUTAMP | AI | Bias current for output amplifiers |
| VREF | AI | Video line reference voltage |
| VCM | AI | Common mode voltage for video amplifier and A/D converter |
| VBG | AI | Bandgap reference voltage or A/D converter |
| VIN+ | AIO | External differential analog input, positive node (in mode 1). Video Line Output (in mode 3). |
| VIN- | AIO | External differential analog input, negative node (in mode 1). VREF Output (in mode 3). |
| VOUT+ | AO | Differential analog output. Positive node |
| VOUT- | AO | Differential analog output. Negative node |
| TEST | | |
| TEST1N | DI* | Bypass video amplifier. Active low |
| CLK_TESTN | DI* | Disconnect CLK input from PH1 PH2 generator and connect PH1_TEST, PH2_TEST. Active low |
| PH1_TEST | DI* | direct PH1 input |
| PH2_TEST | DI* | direct PH2 input |
| VDL_TESTN | DI* | Enable test of video line by enabling VDL_IN. Active low. |
| ONADC | DI* | Power down control for ADC. 1= normal operation |
| ONREF | DI* | Power down control for ADC reference generator. 1=normal operation |
| ONCM | DI* | Power down control for ADC common mode voltage generator. 1= normal operation |
| VDL_IN | AI* | Input to force video line with external voltage |
| VREFP | AIO* | Positive reference voltage of A/D converter |
| VREFN | AIO* | Negative reference voltage of A/D converter |
| VCM2 | AIO* | Common mode voltage of A/D converter |
| SPARE1 | DI* | Spare input pin |
| SPARE2 | DI* | Spare input pin |
| SPARE3 | DI* | Spare input pin |
| SPARE4 | DI* | Spare input pin |
| SUPPLY | | |
| GND | S | Digital ground |
| VDD | S | Digital supply voltage (3.3 V) |
| GNDA | S | Analog ground |
| VDDA | S | Analog supply voltage |
| GNDB | S | Ground for biasing of substrate |
| Vddb | S | Supply voltage for biasing of wells |
| GNDP | S | Ground for pad drivers |
| VDDP | S | Supply voltage for pad drivers |

NOTES:

(1): D = digital line; A= analog line; I= input; O = output, S= supply

All digital inputs have TTL thresholds. All digital inputs have weak (70 Kohm) pull-ups. The pins marked with * can be connected only in CCC64 package.

Package:

64 CCC ceramic 40 mil pin pitch with glass window

Alternatively, 44 CC leadless ceramic 40 mil pitch with glass window

VISTA - Pin cross-reference list

| ADDRESS | | OUTPUT | | CONTROL | | POWER | | TEST | |
|---------|----|--------|----|----------|----|-------|----|-----------|----|
| AC0 | 16 | DOUT0 | 63 | CLK | 12 | GND | 6 | TEST1N | 55 |
| AC1 | 15 | DOUT1 | 62 | OEN | 13 | VDD | 11 | CLK_TESTN | 39 |
| AC2 | 14 | DOUT2 | 61 | VEXT_EN | 35 | | | PH1_TEST | 7 |
| AC3 | 5 | DOUT3 | 60 | | | GNDA | 27 | PH2_TEST | 8 |
| AC4 | 4 | DOUT4 | 59 | IBTL | 21 | VDDA | 28 | VDL_TESTN | 56 |
| AC5 | 3 | DOUT5 | 52 | IBVAMP | 20 | | | ONADC | 42 |
| AC6 | 2 | DOUT6 | 51 | IBOUTAMP | 19 | GNDB | 33 | ONREF | 40 |
| AC7 | 1 | DOUT7 | 50 | VREF | 29 | VDDDB | 34 | ONCM | 41 |
| AC8 | 64 | DOUT8 | 49 | VCM | 30 | | | VDL_IN | 24 |
| | | DOUT9 | 48 | VBG | 22 | GNDP | 53 | VREFP | 26 |
| AR0 | 47 | | | VIN+ | 32 | VDDP | 54 | VREFN | 25 |
| AR1 | 46 | | | VIN- | 31 | | | VCM2 | 23 |
| AR2 | 45 | | | VOUT+ | 18 | | | | |
| AR3 | 44 | | | VOUT- | 17 | | | SPARE1 | 57 |
| AR4 | 43 | | | | | | | SPARE2 | 58 |
| AR5 | 38 | | | | | | | SPARE3 | 9 |
| AR6 | 37 | | | | | | | SPARE4 | 10 |
| AR7 | 36 | | | | | | | | |

DETAILED DESCRIPTION

The architecture of the sensor is shown in figure 1. figure 2 shows detailed circuit diagram. The sensor operates in conjunction with a host microcomputer or microcontroller connected through a data bus carrying the video data to the processor, an address bus which defines the address of the pixel to be read and a set of control lines. As shown in Figure 1, the sensor comprises an array of 320 x 256 pixels, a video amplifier and 10-bit pipeline A/D converter. Single pixel selection is achieved by row and column decoders; the row decoder selects one row and the column decoder selects one of 320 pixels of this row and connects it to the video amplifier. The signal from the video amplifier is converted by the ADC to digital format. Control, timing and interface logic permits simple connection to a digital bus.

Photosensor array

The array of photodiodes converts the incoming light into a continuous current. No charge integration occurs in the sensor and therefore pixels can be read instantaneously at any time. The generated current of the photodiodes is linearly related to the intensity of the incident light. The biasing circuit of the photodiode possesses a logarithmic characteristic which results in an output voltage which is logarithmically correlated to the incident light. A voltage amplifier within the pixel connects the pixel to a vertical bit-line through a switch driven by the row decoder. Each bit-line is then connected to a global video-line through a set of switches driven by the column decoder. The pixels are square and have an area fill-factor of 0.85. Eight dummy rows and columns are placed on the four edges of the array for better photoresponse uniformity. The size of active portion of the photo-diode array is 2.560 mm x 2.048 mm. The 320 x 256 – pixel resolution can be used for ¼ VGA 320 x 240 resolution or for 256 x 256 resolution. Any other type of subsampling is achievable by simple addressing of the desired pixels.

Operation and timing of the camera

A control block provides all the internal timing signals. In a typical sequence of operation, row and column addresses AR AC are supplied by the user, so that a row of pixels is selected by the row decoder and the data from the selected column of pixels is put on the video amplifier via the video-line. The differential video amplifier amplifies the voltage signal of the video-line by a factor of 2. The resulting signal is then converted to digital by the analog-to-digital converter. The A/D conversion is performed by 10-bit pipeline A/D converter which supplies digital output data to the DO bus with a latency time of 5 clock cycles. The total latency from address valid to data output valid is 7 clock cycles.

In normal operation, one pixel is always selected by the binary value present on the two address busses and the camera continuously converts to digital the signal of this pixel. Both row and column address values should be changed on a rising clock edge only and remain stable for the rest of the cycle as they are not internally latched. A master clock CLK provides the timing for the whole circuit.

A set of voltage references and biasing currents are needed for the charge amplifiers and the analog-to-digital converters. These can be conveniently generated with external resistors from the supply voltage. A number of test lines are provided for production testing of the camera and can be ignored in normal operation.

ELECTRICAL CHARACTERISTICS

SENSITIVITY ADJUSTMENT

The following bias adjustment are adequate for typical operation:

| | | |
|--------------------------|-------------|----|
| IBTL ^(*) | 100 | uA |
| IB_VAMP ^(*) | 200 | uA |
| IB_OUTAMP ^(*) | 1 | mA |
| VREF | 850 | mV |
| VCM | 1.50 | V |
| VBG | 1.25 | V |
| VCM2(**) | VCM | |
| VREFP(**) | VCM + 0.5 V | |
| VREFN(**) | VCM – 0.5 V | |

(*) Currents are injected into the device.

(**) Necessary in test mode only. To be left floating during normal operating mode.

MODES DESCRIPTION

The modes of operation are summarised in the table below:

| MODE | VEXT EN | TEST 1N | VDL TESTN | DESCRIPTION |
|------|------------|------------|--------------|---|
| 0 | 1 | 1 | 1 | Normal operating mode. Default, if test-pins are disconnected. |
| 1 | 0 | 1 | 1 | ADC differential inputs are connected to VIN+ and VIN- pins (used as inputs). The sensor array is disconnected. |
| 2 | 1 | 0 | x | Bypass Video Amplifier: the Video Line is connected directly to non-inverting input of ADC and VREF pin is connected to the inverting input. |
| 3 | 0 | 0 | x | Bypass Video Amplifier and Monitoring: besides being connected to the ADC, the Video Line is also connected to VIN+ pin and VREF is also connected to VIN- pin (used as outputs). |
| | x | x | 0 | Disable Sensor Array: the sensor array is turned off and the Video Line is connected to the VDL_IN pin. This function operates in modes 2 and 3. |

Absolute maximum ratings

| | |
|---------------------------------------|-----------------------|
| Operating temperature | -15 °C to 110 °C |
| Storage temperature | - 55 °C to 150 °C |
| Voltage on any pin to V _{SS} | - 0.5 to 4.5 V |
| Power dissipation | 450 mW @ 20 MHz, 3.3V |

Operating conditions

| Symbol | Parameter | Min | Nom | Max | Units |
|-----------------|--------------------------------|-----|-----|-----|-------|
| T _A | Ambient temperature under bias | -15 | | 110 | °C |
| V _{DD} | Digital supply voltage | 3.0 | 3.3 | 3.6 | V |

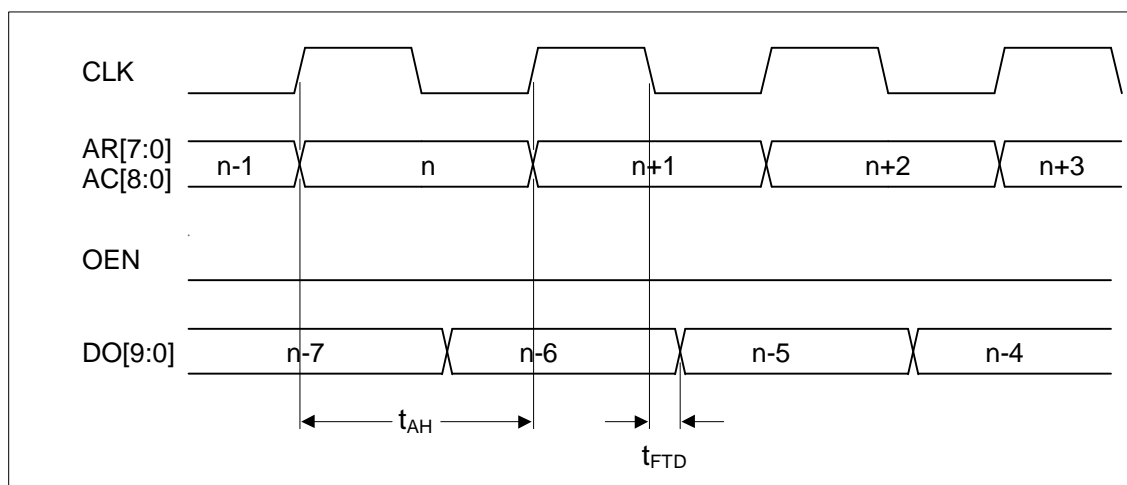
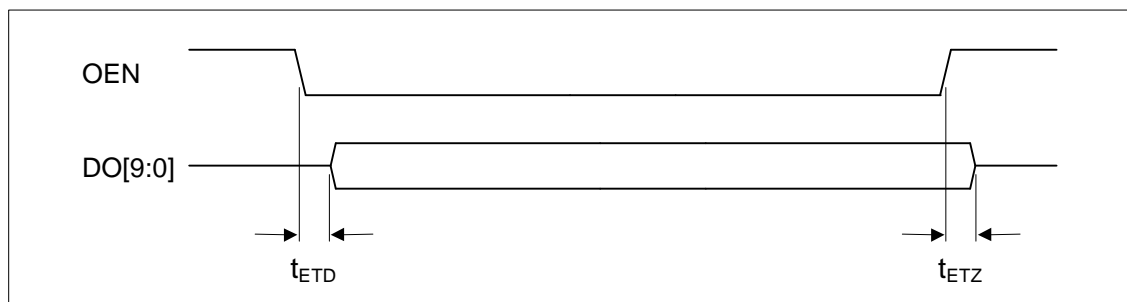
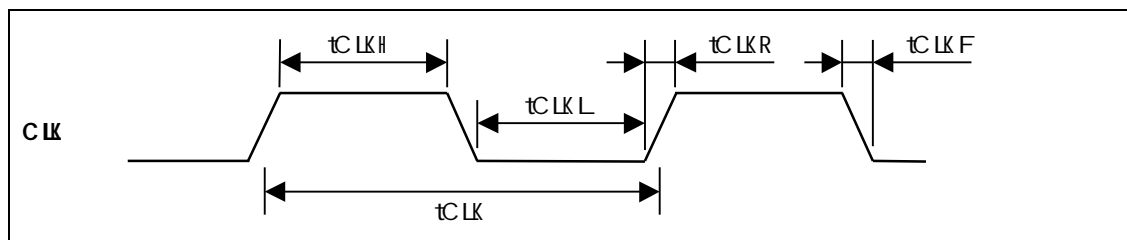
| | | | | | |
|------------------|------------------------|------|--|----|-----|
| F _{CLK} | Master clock frequency | 0.01 | | 20 | MHz |
|------------------|------------------------|------|--|----|-----|

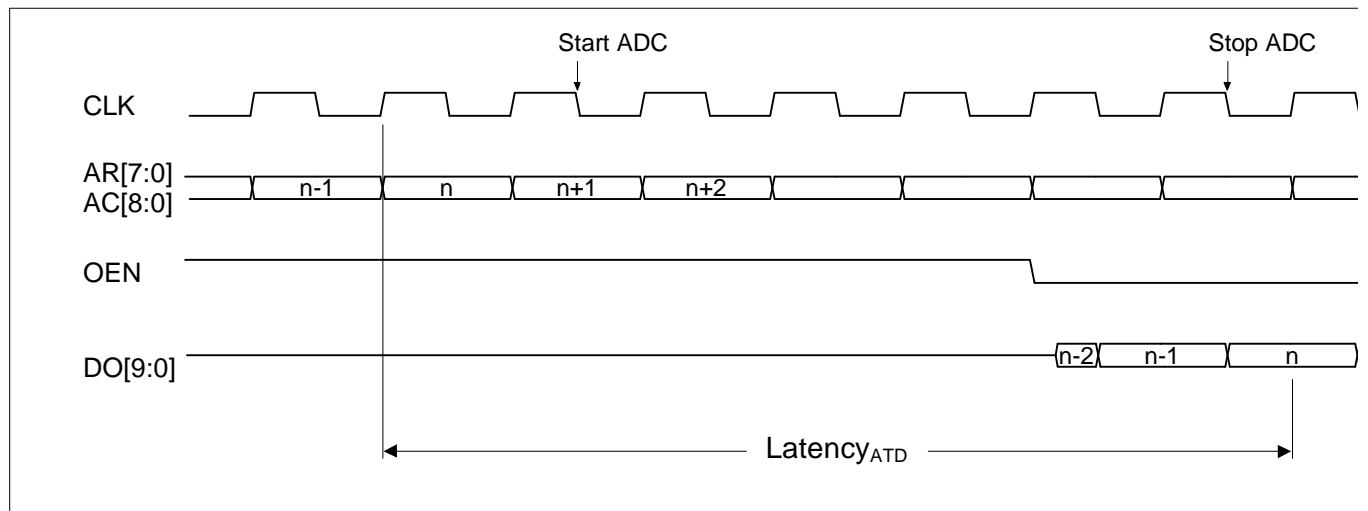
DC characteristics (over specified operating conditions)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------|---|--------------------------|-----------------------|-----|----------------------|-------|
| V _{IH} | Input “high” voltage | TTL inputs | 2.0 | | V _{DD} +0.5 | V |
| V _{IL} | Input “low” voltage | TTL inputs | -0.5 | | 0.8 | V |
| I _{IH} | Input “high” current | TTL inputs | | | ±10 | μA |
| I _{IL} | Input “low” current | TTL inputs | | | ±200 | μA |
| I _{OT} | Output three-state leakage | | | | ±10 | μA |
| V _{OH} | Output “high” voltage | I _{OH} =-4 mA | V _{DD} - 0.4 | | | V |
| V _{OL} | Output “low” voltage | I _{OL} =4 mA | | | 0.4 | V |
| FSLH | Output slew factor (low-to-high transition) | | | | 0.08 | ns/pF |
| FSLH | Output slew factor (high-to-low transition) | | | | 0.05 | ns/pF |
| R _{PU} | Weak pullup on TTL input | | | 70 | | Kohm |
| CPIN | Pin capacitance (any pin to V _{SS}) | | | 5.0 | | pF |
| I _{DD} | Supply current (active mode) | f _{CLK} =20 MHz | | 50 | | mA |

AC PARAMETERS (over specified operating conditions)**External clock drive**

| Symbol | Parameter | Min | Max | Units |
|-------------|-----------------|------|-------|-------|
| $1/t_{CLK}$ | Clock frequency | 0.1 | 16 | MHz |
| T_{CLK} | Clock period | 62.5 | 10000 | ns |
| T_{CLKH} | Clock high time | 20 | | ns |
| T_{CLKL} | Clock low time | 20 | | ns |
| T_{CLKR} | Clock rise time | | 20 | ns |
| T_{CLKF} | Clock fall time | | 20 | ns |

External clock drive waveforms



ELECTRO-OPTICAL CHARACTERISTICS

| | |
|----------------------------|--|
| Array resolution | 320 x 256 |
| Pixel pitch | 8 μm x 8 μm |
| Fill factor | 0.85 |
| Array size | 2.560 mm x 2.048 mm |
| ADC resolution | 10 bit |
| Differential non-linearity | 1/2 LSB |
| Integral non-linearity | 1 LSB |
| Dark Current | t.b.d. nA/cm ² @ 25 C |
| Peak Responsivity | 0.2 A/W @ 600 nm |
| Sensitivity | 2 lux (with f=1.2) |
| Fixed-pattern noise | t.b.d. |
| Dynamic Range | 120 dB |
| Input referred noise | t.b.d. e ⁻ @ 50 % saturation exposure, @ 650 nm |

APPLICATIONS

The complete digital camera only requires the sensor chip and a minimal number of external passive components for the generation of bias voltages and currents for the sensor, a simple power supply and a clock oscillator. Several of these functions are available in the host system and therefore do not require extra components in a typical system.

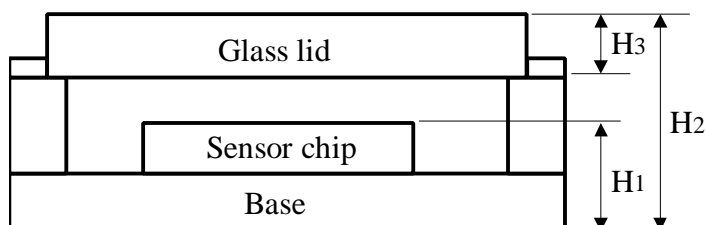
A possible connection to a microprocessor requiring only an external decoder is the following:

| VISTA | | MICROPROCESSOR |
|--------------|----|------------------------|
| D[7:0] | <> | DATA[7:0] |
| A[1:0] | < | ADDRESS[1:0] |
| RDN | < | READN |
| WRN | < | WRITEN |
| CSN | < | DECODED HIGH ADDRESSES |
| EOF | > | INTERRUPT |
| LE | > | INTERRUPT |
| RESETN | < | RESETN |

A typical programming sequence of the processor is the following:

PACKAGE DETAILS

64-pin leadless LCC package with 40 mil pin pitch



Height of photosensor plane from seating plane of package H1 = 1.1 \pm 0.1 mm

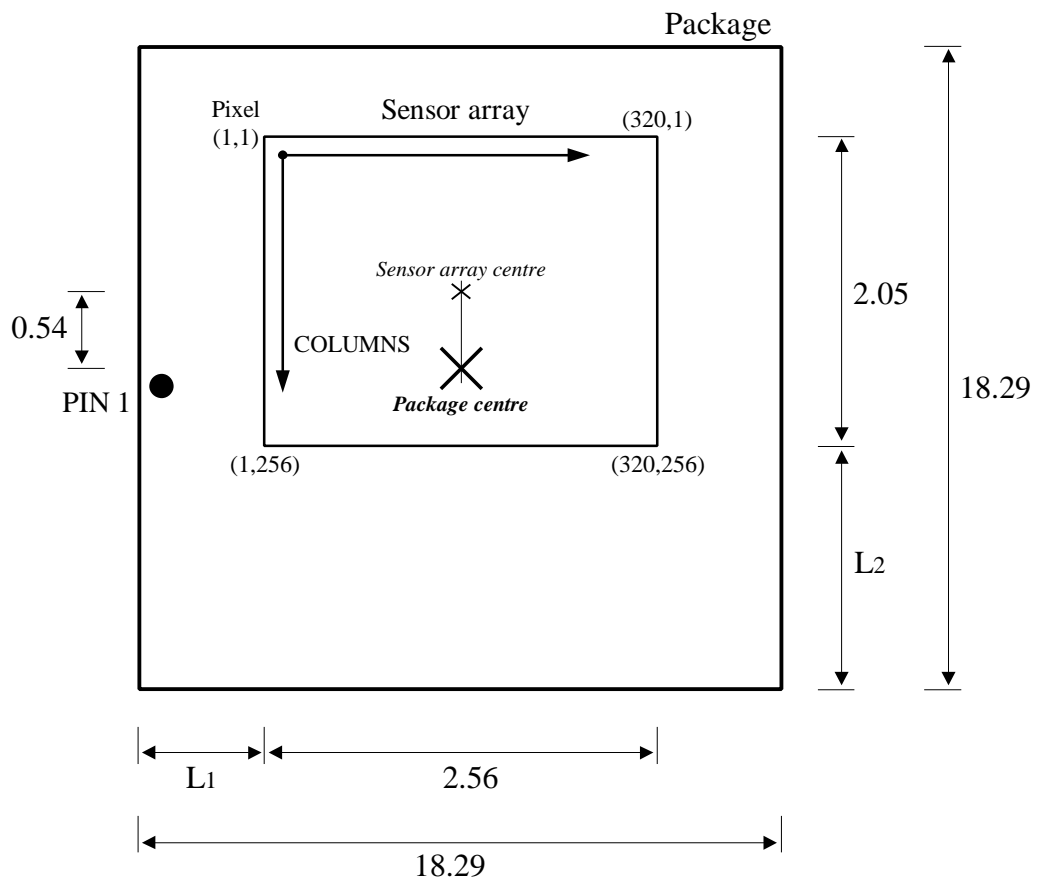
Total height of package including glass lid H2 = 2.0 mm

Thickness of glass lid H3 = 0.5 mm

Lid characteristics: optical glass; n=t.b.d.

SENSOR POSITION

TOP VIEW



Photosensor array position and orientation within package.
All dimensions are in mm.

$$L1 = 7.87 \pm 0.1 \text{ mm}$$

$$L2 = 8.66 \pm 0.1 \text{ mm}$$